

Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination	
		HWANG ET AL.	
Examiner	Art Unit		
Yaima Campos	2185		

SEARCHED

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EIC PLUS search	3/10/2006	YC
PALM and EAST inventor name search	3/10/2006	YC
Text search within subclasses 711/115,156	3/10/2006	YC

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner